Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
09/845,046		
Examiner	Art Unit	
Lena Najarian	3626	

	SEAR	CHED	
Class	Subclass	Date	Examiner
705	2 3	7/28/2006	LN
705	2 3	7/31/2006	LN
604	189	7/31/2006	LN
702	177	7/31/2006	LN
235	462.15	7/31/2006	LN
		·	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	7/28/2006	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	7/31/2006	LN
Proquest (see attached printout)	7/28/2006	LN